

Amendments to the Abstract

In the Abstract:

Please replace the Abstract with the following rewritten Abstract:

~~The invention relates to a scanning microscope for reproducing an object (1), said microscope comprising a light source (2), a spectrally selective element (8) which can be adjusted in an almost infinitely variable manner, a spectrally selective detection device (4) which can be adjusted in an almost infinitely variable manner, an illumination beam path (3) extending from the light source (2) to the object (1), and a detection beam path (5) extending from the object (1) to the detection device (4). According to the invention, the spectrally selective element (8) is used to select light from the light source (2) for illuminating the object; the spectrally selective element (8) is used to mask out the selected light of the light source (2), which is reflected and/or scattered on the object (1), from the detection beam path; and at least one wavelength range of the light extending along the detection beam path (5) can be detected by means of the spectrally selective detection device (4). The present invention is characterised, for the detection of an object (1) at a high scanning speed with an improved signal to noise ratio, in that the illumination beam path (3) and the detection beam path (5) are embodied in the form of a confocal slit scanner.~~

A scanning microscope for imaging an object includes a light source and a spectrally selective detection device. An illumination beam path extends from the light source to the object. A detection beam path extends from the object to the detection device. A spectrally selective element useable to select light from the light source is provided. The spectrally selective element is useable to mask out of the detection beam path the selected light from the light source reflected or scattered on the object. An illumination slit diaphragm is disposed in the illumination beam path and configured to generate a linear illumination pattern in a region of the object. A

detection slit diaphragm is disposed in the detection beam path and configured to detect the light coming from the linear illumination region from a focal plane so as to provide a confocal slit scanner.